Abstracts

An accurate determination of the characteristic impedance matrix of coupled symmetrical lines on chips based on high frequency S-parameter measurements

T.-M. Winkel, L.S. Dutta and H. Grabinski. "An accurate determination of the characteristic impedance matrix of coupled symmetrical lines on chips based on high frequency S-parameter measurements." 1997 MTT-S International Microwave Symposium Digest 3. (1997 Vol. III [MWSYM]): 1769-1772.

A new method has been developed to determine the characteristic impedance matrix of a symmetric coupled lossy two line system on chips. The presented results are based on high frequency measurements of the scattering parameters. A comparison between the measured and analytical calculated results is given and shows excellent agreement.

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